

Search Notes



Application/Control No.

10/527,155

Examiner

Mark A. Chapman

Applicant(s)/Patent under
Reexamination

LEE ET AL.

Art Unit

1756

SEARCHED

Class	Subclass	Date	Examiner
430	108.6	6/19/2007	MC
	108.1		
	137.2		
<i>update</i>		<i>12/07 m.c.</i>	

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
<i>above and</i>		<i>12/07 m.c.</i>	
<i>P6 Pub</i>			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
<i>east</i>	6/19/2007	MC
<i>update</i>	<i>12/07 m.c.</i>	